D2417, SEPTEMBER 1980-REVISED FEBRUARY 1985

- Organized as 16 Words of Four Bits Fach
- Choice of Buffered 3-State or Open-Collector outputs
- Choice of Noninverted or Inverted Outputs
- Typical Access Time . . . 50 ns

description

These monolithic TTL memories feature Schottky clamping for high performance and a fast chip-select access time to enhance decoding at the system level. A three-state output version and an open-collector-output version are offered for both of the logic choices. A three-state output offers the convenience of an open-collector output with the speed of a totem-pole output; it can be bus-connected to other similar outputs, yet it retains the fast rise time characteristic of the TTL totem-pole output. An open-collector output offers the capability of direct interface with a data line having a passive pull-up.

SN54LS189A, SN54LS289A . . . J PACKAGE SN74LS189A, SN74LS289A . . . J OR N PACKAGE (TOP VIEW)

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SN54LS219A, SN54LS319A...J PACKAGE SN74LS219A, SN74LS319A...J OR N PACKAGE (TOP VIEW)

	_			
A0 🗌	1	U_{16}		٧c
Ī	2	15		Α1
R/₩ 🛚	3	14		Α2
D1 [4	13		A3
Q1 [5	12		D4
D2 🗀	6	11		Q4
Q2 🗀	7	10	D	D3
GND [8	9	b	QЗ

write cycle

Information to be stored in the memory is written into the selected address location when the chip-select (\overline{S}) and the write-enable (R/\overline{W}) inputs are low. While the write-enable input is low, the memory outputs are off (three-state = Hi-Z, open-collector = high). When a number of outputs are bus-connected, this off state neither loads nor drives the data bus; however, it permits the bus line to be driven by other active outputs or a passive pull-up.

read cycle

Information stored in the memory (see function table for input/output phase relationship) is available at the outputs when the write-enable input is high and the chip-select input is low. When the chip-select input is high, the outputs will be off.

FUNCTION TABLE

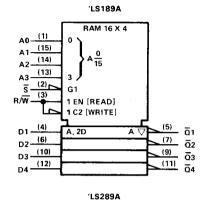
	INF	UTS		<u> </u>			
FUNCTION	CHIP WRITE SELECT ENABLE		'LS189A	'LS289A	'LS219A	'L\$319A	
Write	L	L	Z	Off	Z	Off	
Read	L	н	Complement of Data Entered	Complement of Data Entered	Data Entered	Data Entered	
Inhibit	Н	Х	Z	Off	Z	Off	

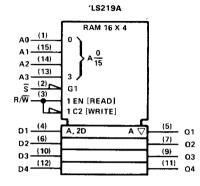
H = high level, L = low level, X = irrelevant, Z = high impedance

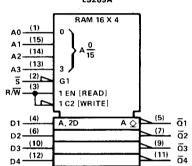
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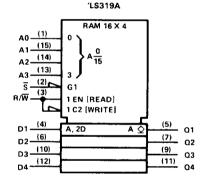
RAMs





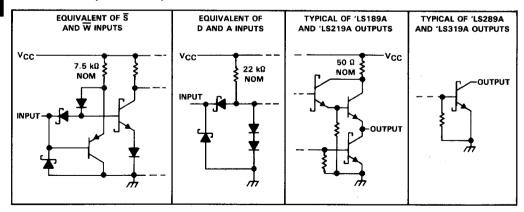






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schematics of inputs and outputs



SN54LS189A, SN54LS219A, SN54LS289A, SN54LS319A SN74LS189A, SN74LS219A, SN74LS289A, SN74LS319A 64-BIT RANDOM-ACCESS MEMORIES

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage	7 V
Off-state output voltage: 'LS189A, 'LS219A	5.5 V
'LS289A, 'LS319A'	7 V
Operating free-air temperature range: SN54LS' Circuits	-55°C to 125°C
SN74LS' Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		1	N54LS1		SN74LS189A, SN74LS219A		UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	1
Supply voltage	ge, VCC	4.5	5	5.5	4.75	5	5.25	V
High-level ou	tput current, IOH			- 1			-2.6	mA
Low-level out	tput current, IOL			12			24	mA
Width of writ	te pulse (write enable low), tw(wr)	100			70			
	Address before write pulse, t _{su(ad)}	01		•	01			1
Setup time	Data before end of write pulse, t _{su(da)}	1001			601			ns
	Chip-select before end of write pulse, t _{SU(S)}	1001			601			
	Address after write pulse, th(ad)	01			10			
Hold time	Data after write pulse, th(da)	01			10			ns
	Chip-select after write pulse, th(S)	01			10]
Operating fre	e-air temperature, TA	- 55		125	0		70	°C

11The arrow indicates the transition of the write-enable input used for reference: 1 for the low-to-high transition, 1 for the high-to-low transition.

electrical characteristics over recommended operating free-air temperature range (unless otherwise

	PARAMETER TEST CONDITIONS [†]			N54LS1			9A 9A	UNIT	
			MIN	TYP [‡]	MAX	MIN	TYP‡	MAX	
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7	L		0.8	
	Input clamp voltage	$V_{CC} = MIN$, $l_1 = -18 \text{ mA}$			- 1.5			1.5	V
Vон	High-level output voltage	$V_{CC} = MIN$, $V_{IH} = 2 V$, $V_{IL} = V_{IL} max$, $I_{OH} = MAX$	2.4	3.1		2.4	3.1		٧
		V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOF	Low-level output voltage	V _{IL} = V _{IL} max I _{OL} = 24 mA					0.35	0.5	L.
	Off-state output current	V _{CC} = MAX, V _{IH} = 2 V,			20	}		20	μA
OZH	high-level voltage applied	$V_{IL} = V_{IL} max$, $V_{O} = 2.7 V$							<u></u>
	Off-state output current,	$V_{CC} = MAX$, $V_{IH} = 2 V$,			- 20			- 20	μА
OZL	low-level voltage applied	$V_{1L} = V_{1L}max$, $V_{0} = 0.4 V$	<u> </u>						<u> </u>
I.	Input current at	V _{CC} = MAX, V _I = 7 V			100			100	μΑ
lj.	maximum input voltage	VCC = IMAX, VI / /				ļ			ļ .
ηн	High-level input current	$V_{CC} = MAX$, $V_{I} = 2.7 V$	1		20			20	μА
TIL.	Low-level input current	$V_{CC} = MAX$, $V_I = 0.4 V$			-0.4	1		-0.4	mA
	Short-circuit output	V _{CC} = MAX	- 30		- 130	-30		- 130	l _{mA}
los	current [§]	VCC - MIAN	100			L.			
lcc	Supply current	V _{CC} = MAX, See Note 2	1	35	60		35	60	mA

¹For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics over recommended operating ranges of TA and VCC (unless otherwise noted)

PARAMETER		PARAMETER TEST CONDITIONS				189A 219A		9A 9A	UNIT	
			MIN	TYP‡	MAX	MIN	TYP [‡]	MAX		
ta(ad)	Access time from address	5.A	0 45.5		50	90		50	80	ns
u\uu,	Access time from chip select (enabl	e time)	C _L = 45 pF,		35	70		35	60	ns
tSR	Sense recovery time		See Note 3		55	100		55	90	ns
-311		from S	$C_L = 5 pF$,		30	60		30	50	Ι
tPXZ	tpxz Disable time from high or low level	from R/W	See Note 3		40	70		40	60	ns

 $^{^{\}ddagger}AII$ typical values are at VCC = 5 V, TA = 25 °.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

[‡]All typical values are at V_{CC} = 5 V, T_A = 25 °C. §Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2: ICC is measured with the write-enable and chip-select inputs grounded, all other inputs at 4.5 V, and all outputs open.

SN54LS289A, SN54LS319A, SN74LS289A, SN74LS319A 64-BIT RANDOM-ACCESS MEMORIES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

			N54LS2 N54LS3		SN74LS289A, SN74LS319A			UNIT
	•	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltag	ge, V _{CC}	4.5	5	5.5	4.75	5	5.25	٧
High-level ou	tput voltage, VOH			5.5			5.5	٧
Low-level out	tput current, IOL			12			24	mΑ
Width of writ	te pulse (write enable low), t _{W(Wr)}	100			70			
	Address before write pulse, t _{su(ad)}	01			01			
Setup time	Data before end of write pulse, t _{su(da)}	1001			601			ns
	Chip-select before end of write pulse, t _{SU(S)}	1001			601		9A MAX 5.25 5.5	1
	Address after write pulse, th(ad)	10			01			
Hold time	Data after write pulse, th(da)	10			01			ns
	Chip-select after write pulse, th(S)	01			01			
Operating fre	e-air temperature, TA	- 55		125	0		70	°C

¹¹The arrow indicates the transition of the write-enable input used for reference: 1 for the low-to-high transition, 1 for the high-to-low transition.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS†			SN54LS289A SN54LS319A			SN74LS289A SN74LS319A			UNIT
					MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
VIH	High-level input voltage				2			2			>
VIL	Low-level input voltage						0.7			0.8	V
VIK	Input clamp voltage	VCC = MIN, I	= -18 m/	4		•	- 1.5			-1.5	V
1	Ui-b land and a second	V _{CC} = MIN, V	/ _{IH} = 2 V,	$V_0 = 2.4 \text{ V}$			20			20	
ІОН	High-level output current	V _{IL} = V _{IL} max,		$V_0 = 5.5 V$			100			100	μА
1/	I am land antant malage	V _{CC} = MIN, V	/ _{IH} = 2 V,	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL	Low-level output voltage	V _{IL} = V _{IL} max		IOL = 24 mA					0.35	0.5	٠
lμ	Input current at maximum input voltage	V _{CC} = MAX, \	/ _I = 7 V				100			100	μΑ
ΊΗ	High-level input current	VCC = MAX, V	$I_1 = 2.7 \text{ V}$				20			20	μA
ΊL	Low-level input current	VCC = MAX, \	/ _I = 0.4 V				-0.4			-0.4	mA
Icc	Supply current	V _{CC} = MAX, S	See Note 2			35	60		35	60	mA

[†]For-conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics over recommended operating ranges of TA and VCC (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		SN54LS289A SN54LS319A			SN74LS289A SN74LS319A			
				MIN	TYP [‡]	MAX	MIN	TYP‡	MAX	1	
ta(ad)	Access time from address	s			50	90		50	80	ns	
t _{a(S)}	Access time from chip se (enable time)		$C_L = 45 \text{ pF}, R_L = 667\Omega,$		35	70		35	60	ns	
tSR	Sense recovery time		See Note 3		55	100		55	90	ns	
^t PLH	Propagation delay time,	from S			30	60		30	50		
	low-to-high-level output (disable time)	from R/W			40	70		40	60	ns	

 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25°.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡]All typical values are at V_{CC} = 5 V, T_A = 25 °C.

Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2: I_{CC} is measured with the write-enable and chip-select inputs grounded, all other inputs at 4.5 V, and all outputs open.